



森美特半导体股份有限公司

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# 产 品 承 认 书

产品类别：肖特基二极管

产品型号：20MQ100

修订部门：研发部

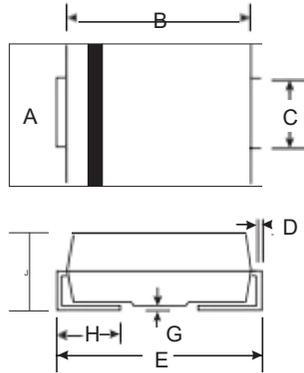
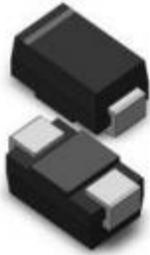
修订日期：2024-11-04

## 一、产品分类：

产品类别型号：20MQ100 类别名称：肖特基二极管

■ 无铅产品

## 二、元器件封装外形尺寸图：



SMA(DO-214AC)		
Dim	Min	Max
A	2.29	2.92
B	4.00	4.60
C	1.27	1.63
D	0.15	0.31
E	4.80	5.59
G	0.10	0.20
H	0.76	1.52
J	2.01	2.62
All Dimensions in mm		

## 三、本体印字方式：

名称	封装方式	本体印字	说明
20MQ100	DO-214AC/SMA	 20B100	 : 品牌 logo 20B100 : 本体代码

## 四、数据表：

### Maximum Ratings and Electrical Characteristics $T_A = 25^\circ\text{C}$ . C unless otherwise specified

SYMBOL	CHARACTERISTICS	VALUES	UNITS
$I_{F(AV)}$	Rectangular waveform	2	A
$V_{RRM}$		100	V
$I_{FSM}$	$t_p = 5 \mu\text{s}$ sine	120	A
$V_F$	2 A pk, $T_J = 125^\circ\text{C}$	0.72	V
$T_J$	Range	- 55 to 150	$^\circ\text{C}$

PARAMETER	SYMBOL	VS-20MQ100-M3	UNITS
Maximum DC reverse voltage	$V_R$	100	V
Maximum working peak reverse voltage	$V_{RWM}$		

PARAMETER	SYMBOL	TEST CONDITIONS	VALUES	UNITS
Maximum average forward current See fig. 4	$I_{F(AV)}$	50 % duty cycle at $T_L = 113^\circ\text{C}$ , rectangular waveform On PC board 9 mm <sup>2</sup> island (0.013 mm thick copper pad area)	2.1	A
		50 % duty cycle at $T_L = 116^\circ\text{C}$ , rectangular waveform On PC board 9 mm <sup>2</sup> island (0.013 mm thick copper pad area)	2	
Maximum peak one cycle non-repetitive surge current See fig. 6	$I_{FSM}$	5 $\mu\text{s}$ sine or 3 $\mu\text{s}$ rect. pulse	120	A
		10 ms sine or 6 ms rect. pulse		
Non-repetitive avalanche energy	$E_{AS}$	$T_J = 25^\circ\text{C}$ , $I_{AS} = 0.5 \text{ A}$ , $L = 8 \text{ mH}$	1.0	mJ
Repetitive avalanche current	$I_{AR}$		0.5	A

**ELECTRICAL SPECIFICATIONS**

PARAMETER	SYMBOL	TEST CONDITIONS	VALUES	UNITS	
Maximum forward voltage drop See fig. 1	V <sub>FM</sub> (1)	2 A	T <sub>J</sub> = 25 °C	0.91	V
		1.5 A		0.85	
		1 A		0.78	
		2 A	T <sub>J</sub> = 125 °C	0.72	
		1.5 A		0.68	
		1 A		0.63	
Maximum reverse leakage current See fig. 2	I <sub>RM</sub>	T <sub>J</sub> = 25 °C	V <sub>R</sub> = Rated V <sub>R</sub>	0.1	mA
		T <sub>J</sub> = 125 °C		1	
Threshold voltage	V <sub>F(TO)</sub>	T <sub>J</sub> = T <sub>J</sub> maximum	0.52	V	
Forward slope resistance	r <sub>t</sub>		78.4	mΩ	
Typical junction capacitance	C <sub>T</sub>	V <sub>R</sub> = 10 VDC, T <sub>J</sub> = 25 °C, test signal = 1 MHz	38	pF	
Typical series inductance	L <sub>S</sub>	Measured lead to lead 5 mm from package body	2.0	nH	
Maximum voltage rate of change	dV/dt	Rated V <sub>R</sub>	10 000	V/μs	

**Note**

(1) Pulse width = 300 μs, duty cycle = 2 %

**THERMAL - MECHANICAL SPECIFICATIONS**

PARAMETER	SYMBOL	TEST CONDITIONS	VALUES	UNITS
Maximum junction and storage temperature range	T <sub>J(1)</sub> , T <sub>Stg</sub>		- 55 to 150	°C
Maximum thermal resistance, junction to ambient	R <sub>thJA</sub>	DC operation	80	°C/W
Approximate weight			0.07	g
			0.002	oz.

**Note**(1)  $\frac{d P_{ot}}{dT_J} < \frac{1}{R_{thJA}}$  thermal runaway condition for a diode on its own heatsink



五、曲线图:

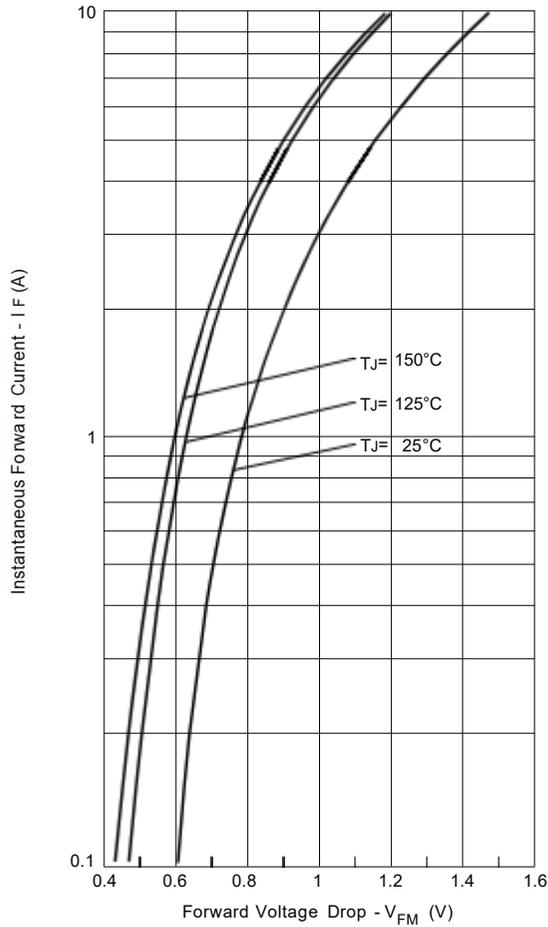


Fig. 1 - Maximum Forward Voltage Drop Characteristics

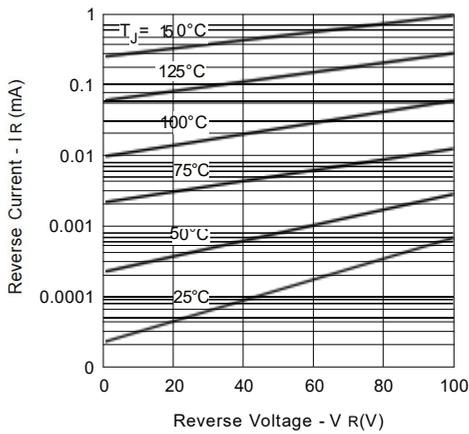


Fig. 2 - Typical Peak Reverse Current vs. Reverse Voltage

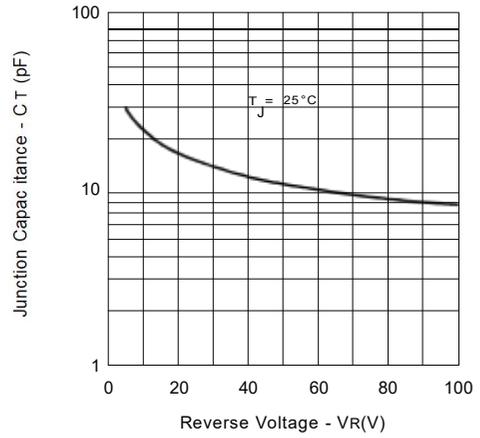


Fig. 3 - Typical Junction Capacitance vs. Reverse Voltage

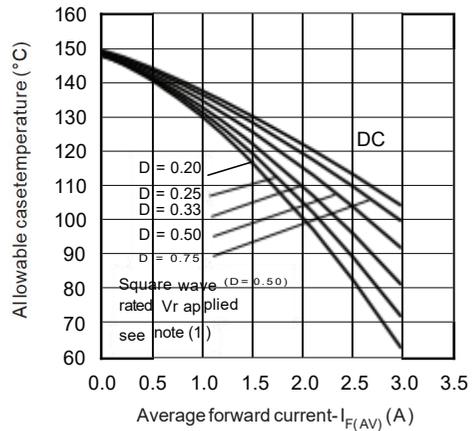


Fig. 4 - Maximum Average Forward Current vs. Allowable Lead Temperature

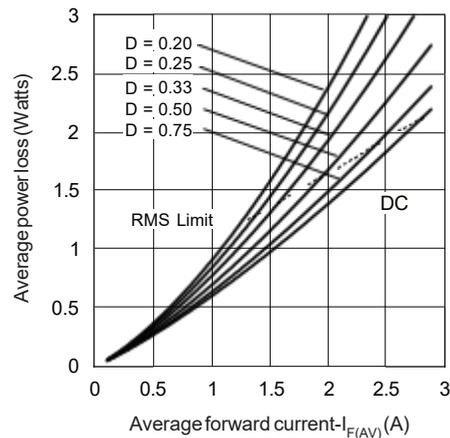
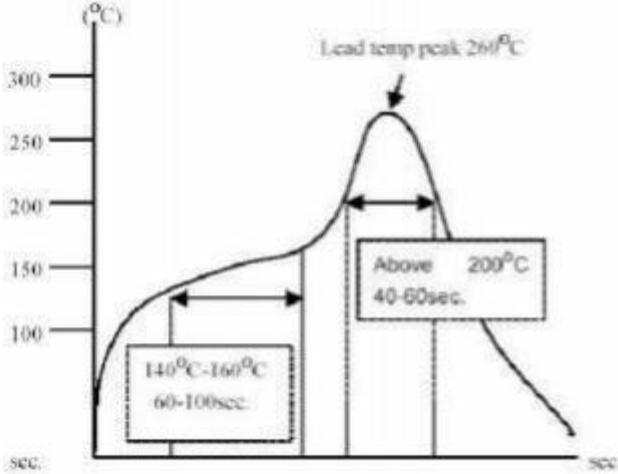


Fig. 5 - Maximum Average Forward Dissipation vs. Average Forward Current



回流焊的温度曲线



六、耐焊接热

温度 280±5℃，时间 10 秒，测试 VZ、IR 符合规范要求。

七、元器件可靠性测试：

Reliability Test 可靠性测试	Test Conditions 测试条件	Sampling Plan 取样计划	Frequency 频率
Solderability Test 可焊性测试	Ta = 230±5℃, time = 3-6sec.	Sample size : 10 pcs Acc: 0/1	每批次抽测一次
Marking Permanence 印字测试	Per as IEC 682-45 method 1, solvent: 1, 1, 1-TCE and ethanol	Sample size : 10 pcs Acc: 0/1	每天每台机抽测一次
Thermal Shock 热冲击	0℃, 1 minute;100℃, 3minute 10 cycles	Sample size :20 pcs Acc: 0/1	各封装产品随机三个型号每月检测一次
High Temperature Storage Test 高温贮存测试	Ta=150℃, 1000 Hours	Sample size :20 pcs Acc: 0/1	各封装产品随机三个型号每月检测一次
Continuous Operation Test (Zener Only) 长期工作寿命测试	Dc voltage applied on reverse bias at full power, 1000hours	Sample size :20 pcs Acc: 0/1	各封装产品随机三个型号每月检测一次
High Temperature/Humidity Storage Test 恒温/ 恒湿测试	Ta=65℃ , RH=98% 100hours	Sample size :20 pcs Acc: 0/1	各封装产品随机三个型号每月检测一次
Pressure cooker 高压蒸煮	15 Psig , TA= 121℃,4H	Sample size :20 pcs Acc: 0/1	各封装产品随机三个型号每月检测一次
Soldering Heat 耐焊接热	Ta=260℃,T= 10s; Dipped up to a place 1-1.5mm apart from its body	Sample size :20 pcs Acc: 0/1	各封装产品随机三个型号每月检测一次

八、包装

- a) 包装应防震、防潮、防压、无破损。
- c) 内包装有出厂检验合格证，生产日期、产品规格型号、内包装数量。
- d) 外包装上有制造厂名称、产品规格型号、内包装数量。